

TMT20N60 / TMF20N60 N-CHANNEL POWER MOSFET

General Description	Product Summary
<p>The TMT20N60 & TMF20N60 have been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications. By providing low $R_{DS(on)}$, C_{iss} and C_{rss} along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs.</p>	<p> V_{DS} 600V I_D (at $V_{GS}=10V$) 20A $R_{DS(on)}$ (at $V_{GS}=10V$) < 0.45Ω 100% UIS Tested 100% R_g Tested </p>



Top View						
TO-220AB		TO-220F				
TMT20N60		TMF20N60				
Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted						
Parameter	Symbol	TMT20N60	TMF20N60	Units		
Drain-Source Voltage	V_{DS}	600		V		
Gate-Source Voltage	V_{GS}	± 30		V		
Continuous Drain Current	I_D	20	20*	A		
$T_C=100^\circ C$		14	14*			
Pulsed Drain Current ^C	I_{DM}	80				
Avalanche Current ^C	I_{AR}	6.5		A		
Repetitive avalanche energy ^C	E_{AR}	630		mJ		
Single pulsed avalanche energy ^G	E_{AS}	1260		mJ		
Peak diode recovery dv/dt	dv/dt	5		V/ns		
Power Dissipation ^B	P_D	250	85	W		
Derate above $25^\circ C$		2.0	0.68			
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		$^\circ C$		
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	T_L	300		$^\circ C$		
Thermal Characteristics						
Parameter	Symbol	TM20N60	TMF20N60	Units		
Maximum Junction-to-Ambient ^{A,D}	$R_{\theta JA}$	65	65	$^\circ C/W$		
Maximum Case-to-sink ^A	$R_{\theta CS}$	0.5	--	$^\circ C/W$		
Maximum Junction-to-Case	$R_{\theta JC}$	0.3	2.5	$^\circ C/W$		

* Drain current limited by maximum junction temperature.

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	600			V
$BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$		0.8		V/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$ $V_{DS}=480\text{V}, T_J=125^\circ\text{C}$			1 10	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$	3.2	3.8	4.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=10\text{A}$		0.37	0.45	Ω
g_{FS}	Forward Transconductance	$V_{DS}=40\text{V}, I_D=10\text{A}$		25		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.69	1	V
I_S	Maximum Body-Diode Continuous Current				20	A
I_{SM}	Maximum Body-Diode Pulsed Current				80	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$	2448	3061	3680	pF
C_{oss}	Output Capacitance		190	273	360	pF
C_{rss}	Reverse Transfer Capacitance		13	22.8	35	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.7	1.4	2.1	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=480\text{V}, I_D=20\text{A}$	48	61	74	nC
Q_{gs}	Gate Source Charge		14	18	22	nC
Q_{gd}	Gate Drain Charge		12	24	36	nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=300\text{V}, I_D=20\text{A}, R_G=25\Omega$		57		ns
t_r	Turn-On Rise Time			125		ns
$t_{D(off)}$	Turn-Off DelayTime			128		ns
t_f	Turn-Off Fall Time			88		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	384	480	580	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$	8	10.5	13	μC

A. The value of R_{0JA} is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{0JA} is the sum of the thermal impedance from junction to case R_{0JC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. $L=60\text{mH}, I_{AS}=6.5\text{A}, V_{DD}=150\text{V}, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

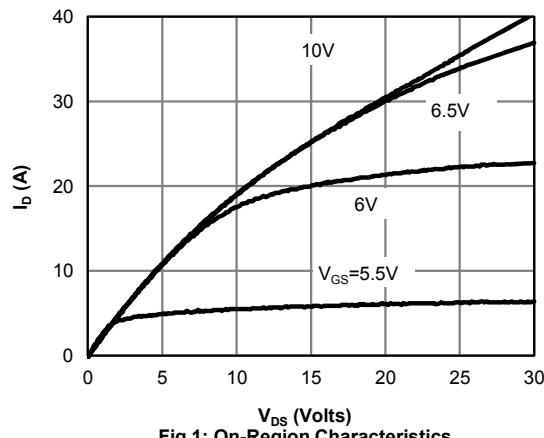


Fig 1: On-Region Characteristics

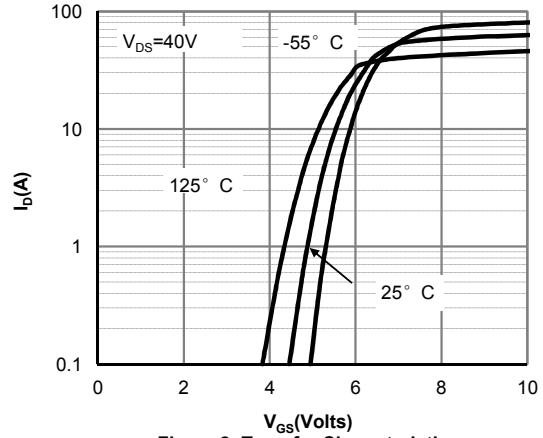


Figure 2: Transfer Characteristics

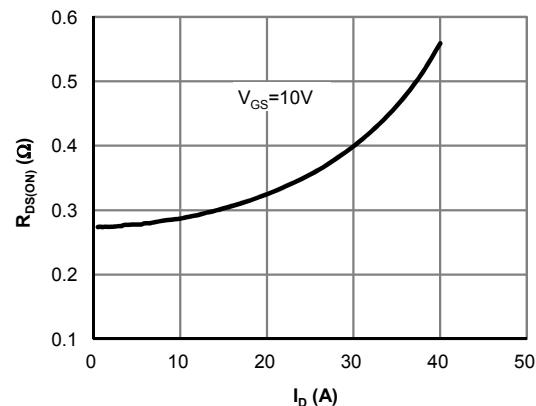


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

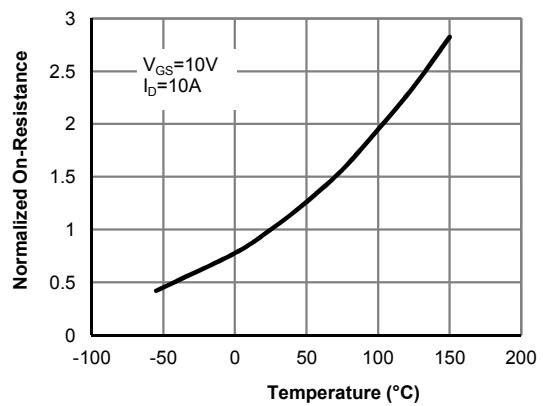


Figure 4: On-Resistance vs. Junction Temperature

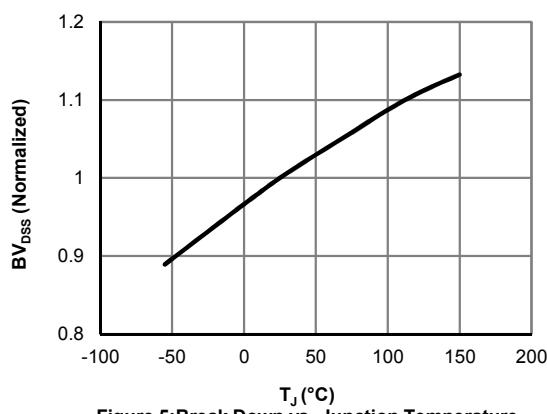


Figure 5: Break Down vs. Junction Temperature

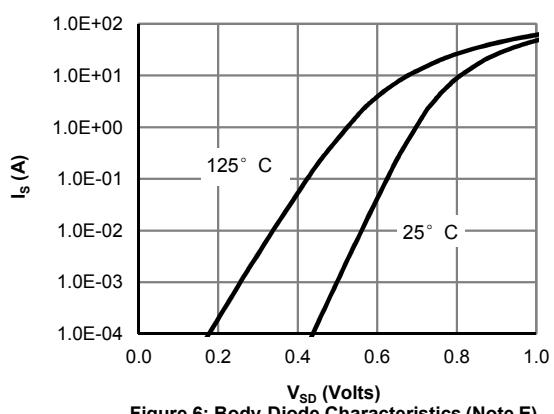


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

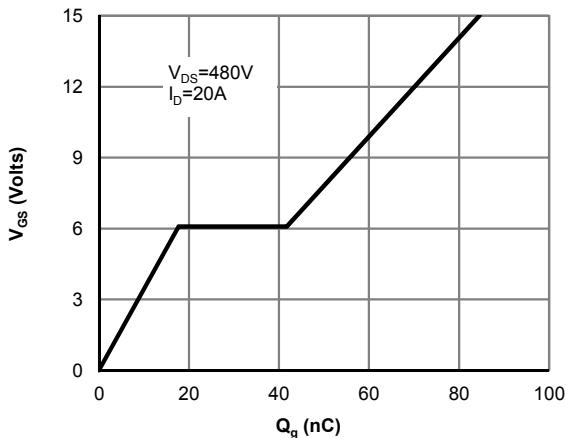


Figure 7: Gate-Charge Characteristics

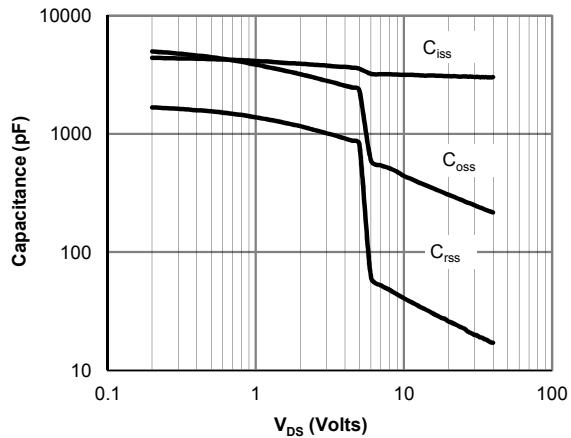


Figure 8: Capacitance Characteristics

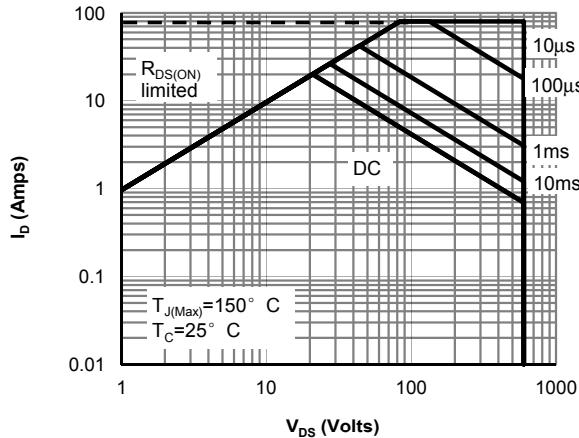


Figure 9: Maximum Forward Biased Safe Operating Area for AOT20N60 (Note F)

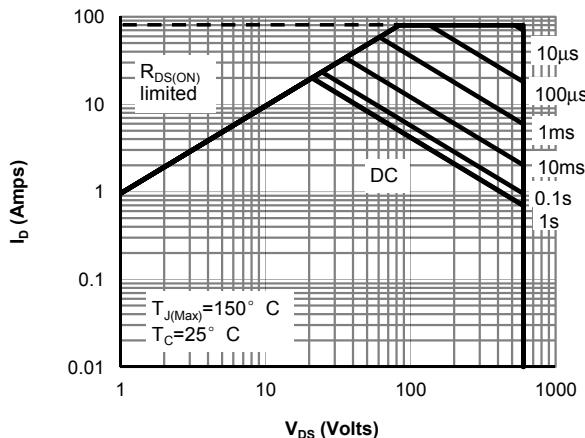


Figure 10: Maximum Forward Biased Safe Operating Area for AOTF20N60 (Note F)

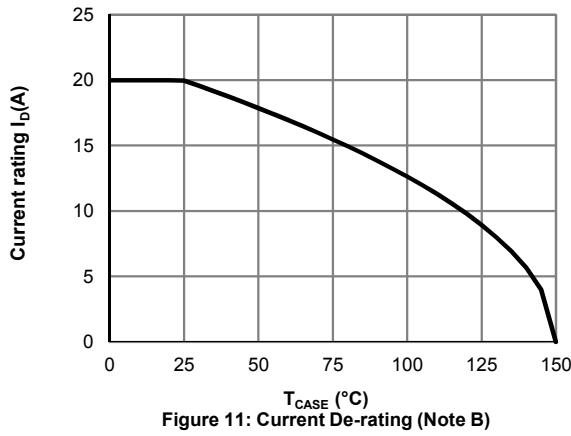


Figure 11: Current De-rating (Note B)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

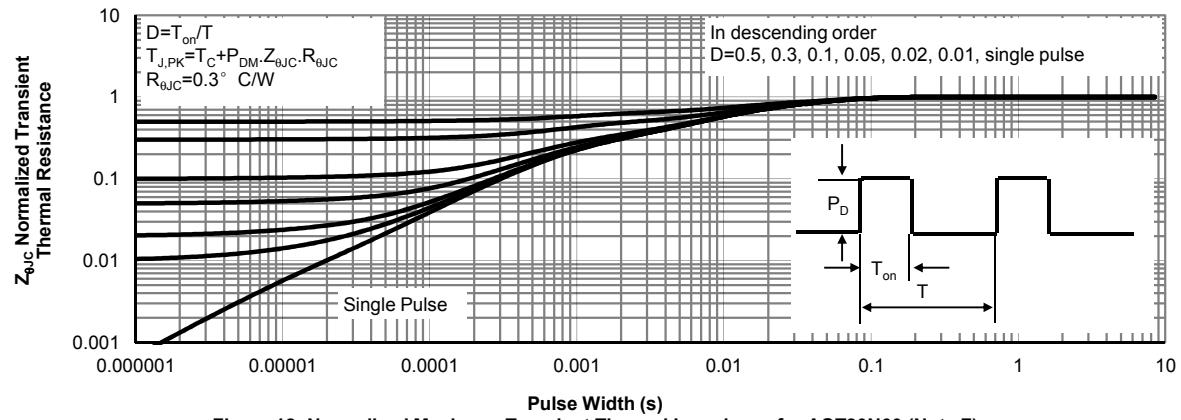


Figure 12: Normalized Maximum Transient Thermal Impedance for AOT20N60 (Note F)

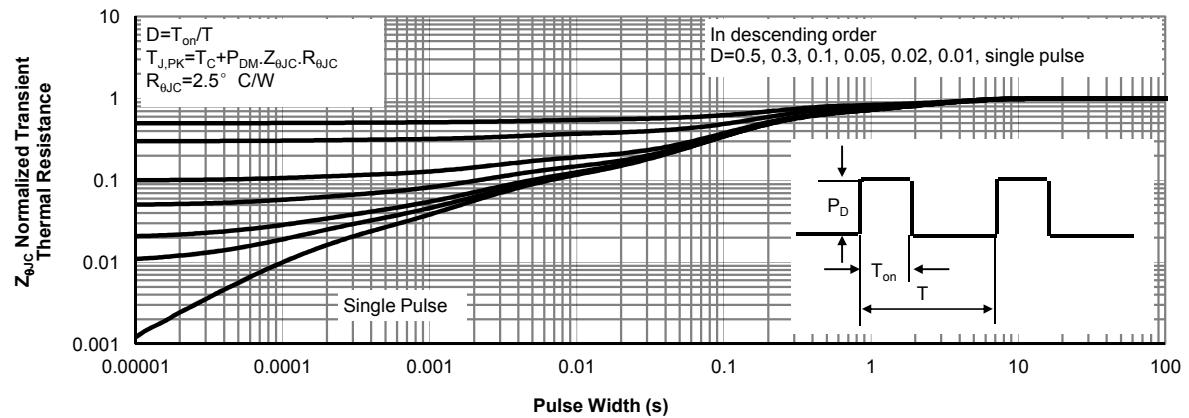
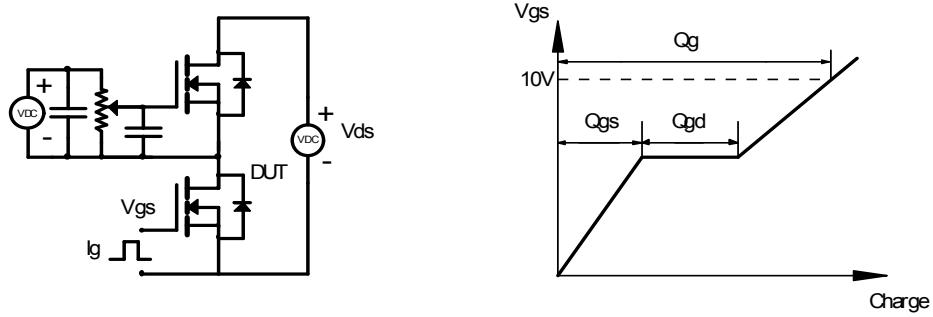
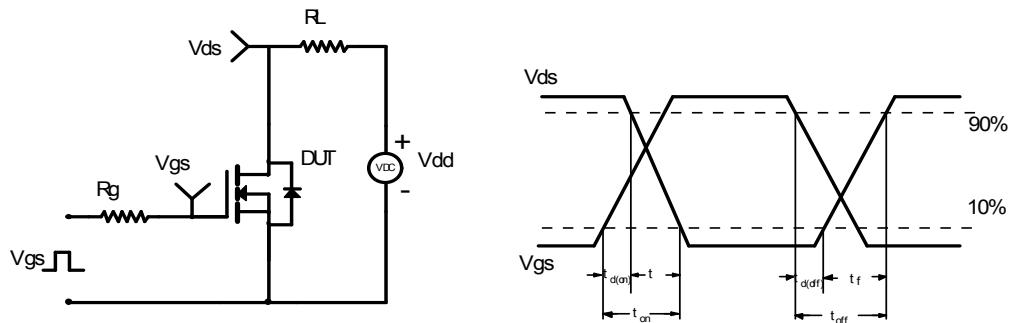


Figure 13: Normalized Maximum Transient Thermal Impedance for AOTF20N60 (Note F)

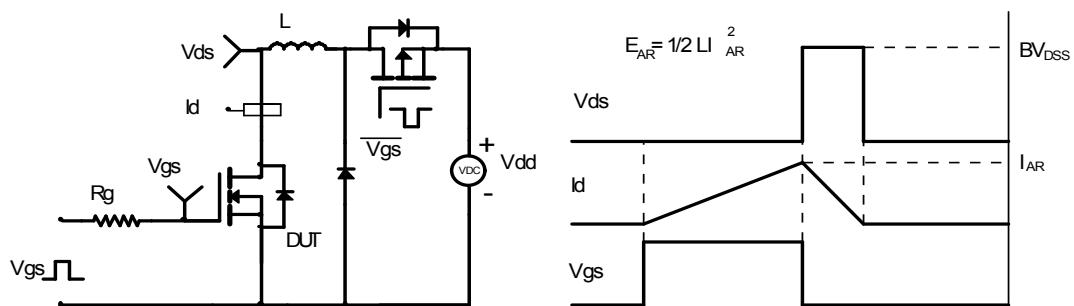
Gate Charge Test Circuit & Waveform



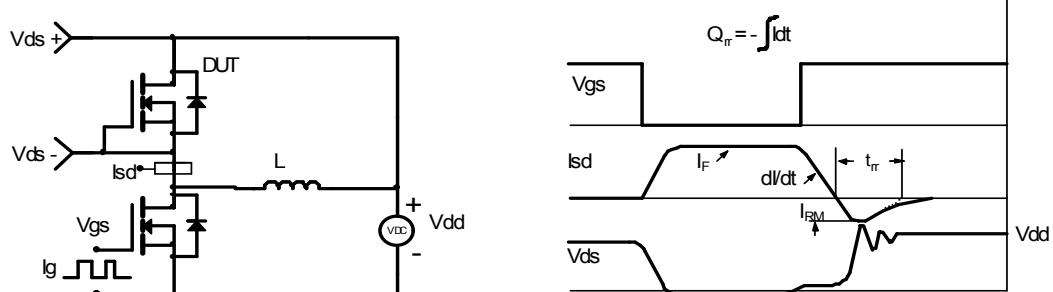
Resistive Switching Test Circuit & Waveforms



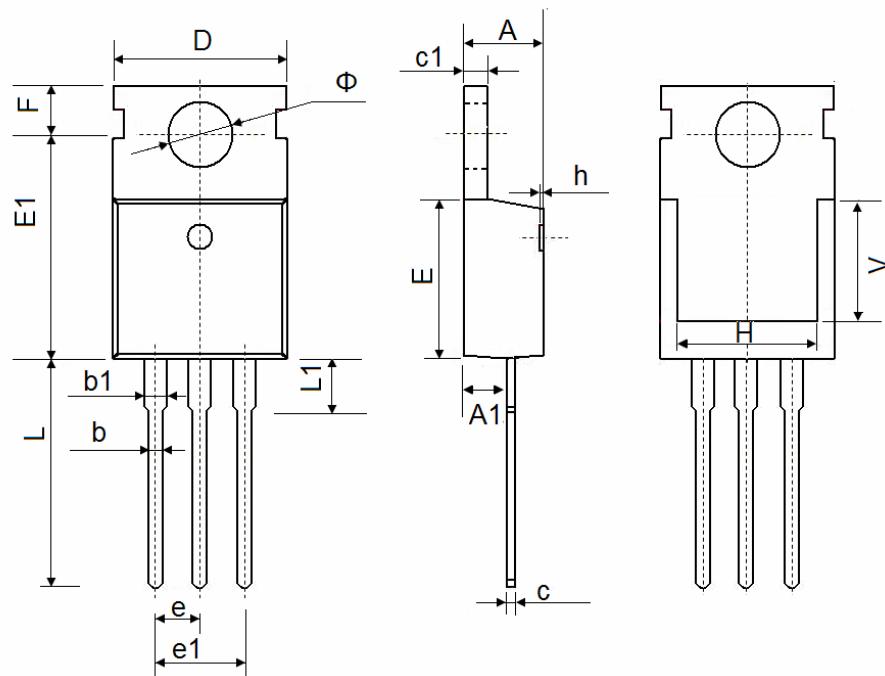
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

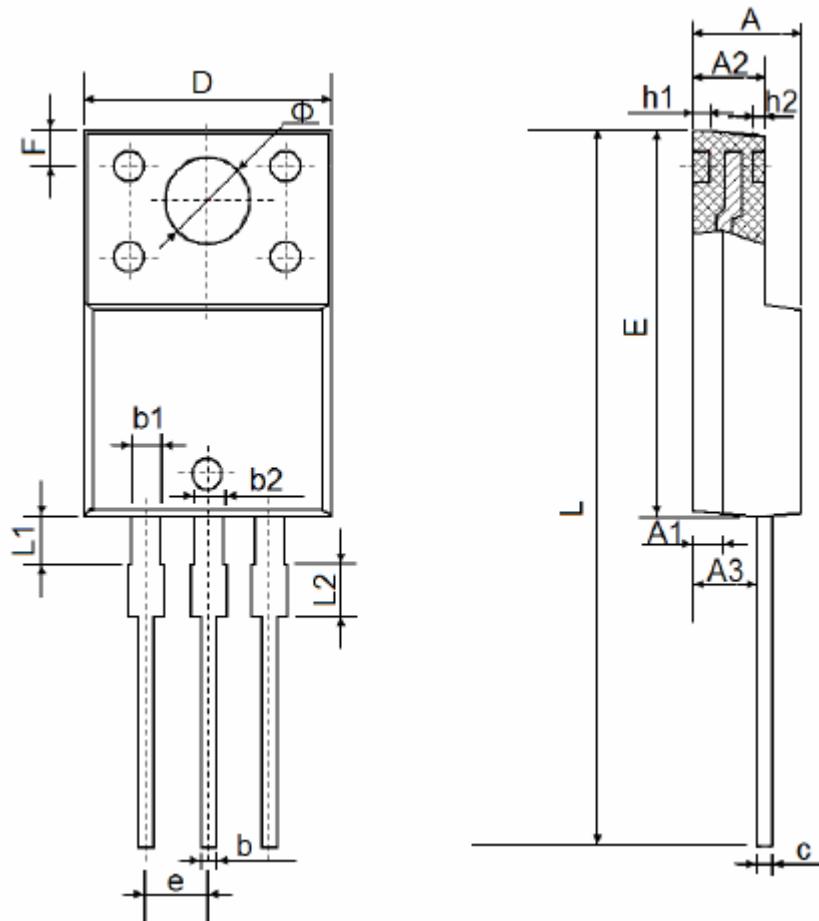


TO-220AB Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.400	4.600	0.173	0.181
A1	2.250	2.550	0.089	0.100
b	0.710	0.910	0.028	0.036
b1	1.170	1.370	0.046	0.054
c	0.330	0.650	0.013	0.026
c1	1.200	1.400	0.047	0.055
D	9.910	10.250	0.390	0.404
E	8.9500	9.750	0.352	0.384
E1	12.650	12.950	0.498	0.510
e	2.540 TYP.		0.100 TYP.	
e1	4.980	5.180	0.196	0.204
F	2.650	2.950	0.104	0.116
H	7.900	8.100	0.311	0.319
h	0.000	0.300	0.000	0.012
L	12.900	13.400	0.508	0.528
L1	2.850	3.250	0.112	0.128
V	7.500 REF.		0.295 REF.	
Φ	3.400	3.800	0.134	0.150

TO-220F Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.300	4.700	0.169	0.185
A1	1.300REF		0.051REF	
A2	2.800	3.200	0.110	0.126
A3	2.500	2.900	0.098	0.114
b	0.500	0.750	0.020	0.030
b1	1.100	1.350	0.043	0.053
b2	1.500	1.750	0.059	0.069
c	0.500	0.750	0.020	0.030
D	9.960	10.360	0.392	0.408
E	14.800	15.200	0.583	0.598
e	2.540TYP.		0.100TYP	
F	2.700REF		0.106REF	
Φ	3.500REF		0.138REF	
h1	0.800REF		0.031REF	
h2	0.500REF		0.020REF	
L	28.000	28.400	1.102	1.118
L1	1.700	1.900	0.067	0.075
L2	1.900	2.100	0.075	0.083